Issue Classification

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SHIMOMURA ET AL.

Applicant(s)/Patent Under Reexamination

Examiner

Leung, Wai Lun

Art Unit

2613

ORIGINAL					INTERNATIONAL CLASSIFICATION										
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Leung, Wai Lun 1/29/08 (Assistant Examiner) (Date) SUF			JASON CHAN ISORY PATENT EXAMINER					Total Claims Allowed:							
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(Legal Instruments (Date) Examiner)		(Primary	Examiner)	er) (Date)						1			1		